Preface

Plenary lectures
Interface science--knowing more about less
The refinement of oxide structures
Advanced spatially resolved electronic structure analysis
Unusual incommensurate, modulated and disordered structures in refractory metal disilicides

Interfaces and surfaces
Three-dimensional atomic scale analysis of interfaces
Composition of grain boundaries and interfaces: a comparison of modern analytical techniques using a 300 kV FEGTEM
Atomic resolution Z-contrast imaging of grain boundaries in Ag-sheathed BSCCO high-T\textsubscript{c} superconducting tapes
Dewetting behaviour of reactive silicate glass films on single-crystal ceramic substrates
High spatial resolution interface chemistry investigations on spin-polarized magnetic tunnel junctions
Grain boundary observation in a SrTiO\textsubscript{3} ceramic condenser
Microstructures of Ag-based metal electrode-PZT electroceramic interfaces
Chemical bonding of intergranular amorphous layers in high-purity beta-SiC ceramics
A scanning electron microscopic analysis of hot-rolled steel/vitreous enamel layer
Obtaining bonding information from EELS near-edge structures: grain-boundaries in NiAl
Structure modelling by molecular dynamics: analysis of TEM images of bonded interfaces
Influence of Cr\textsuperscript{+} and Nb\textsuperscript{+} substrate sputter cleaning on the formation of Ti\textsubscript{l-x}Al\textsubscript{x}/steel interfaces generated in a combined cathodic arc/unbalanced magnetron deposition system
Metal-ceramic interface characterization of capacitor-discharge joined alumina

Scanning electron microscopy
Simplified aberration corrector for low-voltage SEM
Temperature and energy dependence of SEM dopant contrast
Probing nitride thin films in 3 dimensions using a variable energy electron beam
Contrast formation in the environmental scanning electron microscope--imaging liquid-liquid systems
Magnetic contrast in a focused ion beam microscope
Post-failure examination of a new body armour textile by the use of an environmental scanning electron microscope
Automatic surface reconstruction using SEM images based on a new computer vision approach
Simulation of a low voltage SEM objective lens with through the lens secondary electron detection  p. 111
Measurement of small misorientations using electron backscatter diffraction  p. 115
Preliminary experiments on grazing-exit electron probe microanalysis (GE-EPMA)  p. 119
X-ray spectrometry in SEM and elements of the first transition series  p. 123
Electron crystallography
Energy production in biological systems probed by electron crystallography  p. 127
Results of a pilot experiment on direct phase determination of diffracted beams in TEM  p. 133
EELS of Bloch waves in wedge-shaped crystals  p. 137
Inversion of dynamic scattering: determination of local object thickness and orientation  p. 141
Measurement of higher-order correlation functions in amorphous materials via coherent microdiffraction  p. 145
Convergent beam electron diffraction analysis of [beta]- and [gamma]-Zn[subscript 3](VO[subscript 4])2 in V[subscript 2]O[subscript 5]-doped ZnO varistors  p. 149
The nanoscale structure of the B and I[subscript W] phases in yttrium and erbium SiAlONs  p. 153
Crystal structure of lead pyrobiolate  p. 157
Using crystal wedges to solve the inverse scattering problem  p. 165
Analytical electron microscopy
Quantitative compositional imaging with energy-filtering TEM  p. 169
Application of multivariate statistical analysis to complex grain boundary microstructures  p. 175
Fourier deconvolution of image spectra: the removal of plural scattering from energy-filtered series  p. 179
Core-hole effects in the EELS spectra of the B K-edge in aluminium and titanium diboride  p. 183
Calculations of the He 1s[superscript 2] [right arrow] 1s2p energy shift observed in STEM experiments on helium bubbles in irradiated materials  p. 187
Operation modes of a TEM monochromator  p. 191
Cancelling energy drift in a PEELS spectrometer  p. 195
PEELS studies of the sulphur L[subscript 2.3] and metal L[subscript 2.3]-ELNES in sulphur bearing minerals  p. 199
ELNES investigations of the structure and electronic properties of chromium spinels  p. 203
Microstructure and compositional behaviour of InGaN/GaN multiple quantum well structures  p. 207
Compositional mapping of nanoscale metallic multilayers: a comparison of techniques  p. 211
ELNES investigation of the oxidation of AIN  p. 215
ALCHEMI on the O-phase (Ti$_2$AlNb) p. 219
Operation of the fringe field monochromator in field emission STEM p. 223
Comparison of the relative merits of techniques for the modelling of electron energy loss near edge structure (ELNES) p. 227
Monte Carlo calculation and experimental measurement of electron backscattering from solids p. 231
Calibration of the relationship between white-line intensity and valence states for the first transition series p. 235
Compositional mapping in the EFTEM using image spectroscopy p. 239
Investigation of gold nano-particles by energy-filtered imaging p. 243
High resolution x-ray spectrometers for material analysis p. 249
High resolution electron microscopy p. 253
HRTEM and nano-analytical study of metastable precipitates in aluminium alloy 6061 p. 259
Comprehensive characterization of a FEGTEM p. 263
Interface structure retrieval by HREM: from entropy maximization to R-factor fits p. 267
Accurate characterization of CCD cameras for electron detection p. 271
The structure of FeCo/Ag multilayers p. 275
Can energy filtered Fresnel imaging be used to determine the width of magnetic domain walls? p. 279
On the crystal structure of Al$_2$CuMg, S', in Al-Cu-Mg alloys p. 283
The direct determination of magnetic induction maps from Lorentz images p. 287
Thermal diffuse phonon scattering and the HREM contrast mismatch problem: an update p. 291
Indirect super resolved microscopy in the TEM p. 295
Comprehensive automation of the TEM: a new method for the accurate determination of the imaging conditions for arbitrary specimens p. 299
HREM studies of an electron beam induced morphological rearrangement in acicular ZnO p. 303
In situ structural modification of Nb$_{8-n}$W$_{9+n}$O$_{47}$ (n = 0-4) in a gas reaction cell transmission electron microscope p. 307
Advanced scanning probe techniques p. 311
Magnetic force microscopy of soft magnetic films p. 315
Electrons and photons: exploiting the connection p. 319
Subangstrom resolution imaging using annular dark-field STEM p. 323
Optimizing the STEM performance of the JEOL 2010 F 200 kV FEGTEM p. 327
Electron energy loss studies at dislocations in GaN p. 331
Electron spectroscopy from outside--aloof beam or near field? p. 335
Magnetic force microscopy of recording heads p. 339
[\sigma]3 growth in Al thin films on Al$_2$O$_3$ observed by FIB microscopy p. 339
Measuring lens parameters from coherent Ronchigrams in STEM p. 343
Secondary ion mass spectrometry for evaluating boron distributions within the microstructure of ferritic steels

The electron optics of cold field emitters

Ceramics/carbon/composites

Electron microscopy of real ceramics

Influence of additives on microstructural evolution of MgO-C refractories

Comparative study of properties of DLC films by electron energy loss spectroscopy and x-ray reflectivity

Nano-EELS characterization of multi-element nanostructures

HREM and EELS analysis of fullerene-like carbon films

Environmental scanning electron microscopy of hydrated refractory oxides

Preparation of electron transparent SiC monofilaments using focused-ion-beam lithography techniques

TEM, EDX and EELS study of CN[subscript x] and Si-doped CN[subscript x] thin films

Microstructure of commercial bone china

ELNES studies of the carbon K-edge in Ta[subscript x]Ti[subscript 1-x] whiskers

The composition and structure of C-S-H in blended cement pastes containing fly ash

Microstructural evolution on firing low cement castable refractories

Increasing the hydration resistance of burnt dolomite steelmaking flux through microstructural design

Microstructure of high strength TiN/TiB[subscript x] multilayered ceramic coatings

Electron microscopy studies of municipal sludge contaminated marine clay

Microstructural studies of CVD diamond films by transmission electron microscopy

Transmission electron microscopy studies of La[subscript 2]O[subscript 3]-doped [alpha]-SiAlON ceramics

Direct phase transformation from the intermediate carbon phase (ICP) into graphite

Polymerization of C[subscript 60] and C[subscript 70] under thermobaric treatment

Metals/intermetallics

Microstructural characterization by high resolution electron backscattered diffraction in the FEGSEM--competition for the TEM?

Microanalysis of precipitates in Ti-Al alloy

ALCHEMI studies of B2 Nb-Al-V alloys

Development of microstructure in mechanically alloyed FeAl

Dissolution behaviour of precipitates in the HAZ of microalloyed steels

Precipitation in superaustenitic stainless steels with partial replacement of Mo by W

Microstructural characterization of molybdenum disilicide consolidated by hot isostatic pressing
The microstructure of clean mechanically alloyed titanium-titanium boride alloys p. 459

Dislocations in a multiphase Ni-Al-Fe alloy p. 463

Determination of the distribution of NbC precipitates in novel microalloyed steels p. 467

Microstructural study of arc-melted and melt-spun Ti[subscript 3]Al-Si alloys p. 471

Dislocation networks in single crystal MoSi[subscript 2] deformed at high temperatures p. 475

Microstructural characterizations of Cu, Sn containing low carbon steels p. 479

Electron microscopy studies of the oxidation of Nd-Fe-B magnets p. 483

Investigation of formation and annihilation behaviours of athermal [omega]-phase crystals in a Ti-Mo alloy formed by cooling to 77K using in situ dark field imaging and in situ HREM methods p. 487

The metastable C40 structure in sputtered MoSi[subscript 2] thin films p. 491

Dislocation structures of TiAl single crystal compressed along the [110] and [132] directions at room temperature p. 495


Microstructural study of Nd-Fe-Co-Ga-B magnet during the hydrogenation disproportionation process p. 503

Evolution of microstructure in a direct laser-fabricated TiAl component p. 507

TEM-PEELS study of ultrafine precipitation in microalloyed steels p. 511

Catalysts/sensors/environmental materials

Thin film structures formed from metallic nanoparticles; manipulation of the self-assembly process p. 515

Investigation of redox-cycled Ce-Zr mixed oxides for automotive catalysts by electron microscopy p. 521

Crystal growth of nanocrystalline SnO[subscript 2] thin films p. 525

Domain structure and tetragonality in manganese based spinels p. 529

Supported nanocrystals: watching every move p. 533

Detection and quantification of small misalignments in nanometer-sized particles on oxide support systems by the analysis of plan view HREM images p. 537

HREM analysis of the nanostructure/oxygen buffering capacity relationship in a Rh/CeTbO[subscript x] catalyst p. 541

HRTEM studies of the aggregation of size-selected Ag clusters deposited onto graphite p. 545

Observations of nanoporous haematite derived from the thermal decomposition of sulphated goethite p. 549

Low temperature nanogrowth of carbon on a Ni-silica catalyst during the hydrodechlorination of chlorobenzene p. 553

Catalysed carbon deposition on austenitic stainless steel p. 557

Observations of non-close-packed arrangements in multilayers of passivated gold clusters p. 561

Electron microscopy characterization of porous ceramic bodies p. 565
In situ electron microscopy of CeO$_2$ and CeO$_2$-ZrO$_2$ reduction

Semiconductors/superconductors

The role of TEM in semiconductor device development and manufacture

Cathodoluminescence studies of InGaN/GaN layers in the scanning electron microscope

TEM nanoscale analysis of InAs quantum dots grown on GaAs by MBE

Characterization of silicon nanocrystals in silica and correlation with luminescence

Secondary-phase precipitation and surface morphology variations in photolithographically patterned YBa$_2$Cu$_3$O$_{7-x}$/PrBa$_2$Cu$_3$O$_{7-x}$ multilayer device structures

Characterization of ohmic contact to n-GaN using transmission electron microscopy

Arsenic dopant profiling around trench capacitors in a memory chip using EDX in a field-emission TEM/STEM

Characterization of TiN/Ti/CoSi$_2$ interfacial reaction layer by spectrum line imaging

Microstructure of laser-ablated La$_2$CuO$_4$F$_x$ thin films on SrTiO$_3$

The determination of the composition of InAs quantum dots in a GaAs matrix using STEM

Observation of an intense piezoelectric field across a GaN/InGaN/GaN quantum well by off-axis electron holography

Author index

Subject index

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